

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	2	"20050114094"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 14:31
S2	18	"lithography optimization"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:32
S4	8	S2 stack	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 14:45
S5	2	S4 reflectivity	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 13:55
S6	10	"optimal reflectivity value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 14:48
S7	6	"reflectivity optimization"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:20
S11	0	"lithography optimiza\$8"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:13
S12	18	lithography adj optimiza\$8	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:13
S13	108	lithography adj5 optimiza\$8	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:14
S14	98	lithography adj4 optimiza\$8	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:14

S15	318	lithography with optimiza\$8	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:16
S17	1	S15 "R+ S"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:17
S18	0	S15 "Reflectivity plus Sensitivity"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:17
S19	0	"Reflectivity plus Sensitivity"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:17
S20	2	"Reflectivity" with "Sensitivity" with cost with function	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:18
S21	30	"Reflectivity" with "Sensitivity" with cost	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:18
S22	2	"Reflectivity" with "Sensitivity" with lithography	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:19
S23	5014	"R+ S"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:19
S24	16	S23 reflectivity sensitivity	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:20
S26	55	S23 lithography	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:20
S27	13169	Reflect\$8 with optimiz\$8	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:21

S28	3644	(Reflect\$8 optimiz\$8).ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:21
S29	114	S28 lithography	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:22
S30	37	S29 refraction	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:23
S32	0	(reflectiv\$6 optimiz&7).ti.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:23
S33	27	(reflectiv\$6 optimiz\$7).ti.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:24
S34	477	reflectivity optimization multilayer stack	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:25
S35	145	reflectivity optimization multilayer stack lithography	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:34
S36	2	S35 parameter extrema variable	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:26
S37	1	S35 "R+ S"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:29
S38	21322	Lithography.ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:39
S40	0	S38 (optimiz\$7 reflectiv&5). ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:35

S41	12	S38 (optimiz\$7 reflectiv\$5).ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:35
S42	0	S38 (optimal refraction stack).ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:40
S43	2	(optimal refraction stack).ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:40
S44	13	(optim\$8 refraction stack).ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:44
S45	2	extrema with cost with sensitiv\$6	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:45
S46	2	extrema with cost with reflectiv\$6	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:45
S47	2	extrema with reflectiv\$6 with input	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:47
S48	2	extrema same reflectiv\$6 same multilayer same stack	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:47
S49	54	sensitiv\$6 same reflectiv\$6 same multilayer same stack	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:49
S50	177134	Photolithography or lithography	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:49
S51	4	(lithography same optimization) (multilayer with stack)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:52

S52	3	S51 reflectiv\$6	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/07 16:52
S53	2	"6471945".pn.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/13 15:39
S54	41	("2197719" "3052552" "3664962" "3872021" "3912817" "4148872" "4150112" "4156715" "4156716" "4157385" "4159315" "4160054" "4160820" "4208431" "4217368" "4224345" "4271199" "4352825" "4585649" "4753790" "4828845" "4842762" "4952407" "5017385" "5073389" "5256402" "5380530" "5391315" "5629035" "5645821" "5698215" "5713738" "5736175" "5756074" "5824291" "5879728").PN. OR ("6471945").URPN.	US_PGPUB; USPAT; USOCR	AND	ON	2007/03/13 15:41
S56	0	(multilayer stack).ab. thickness "index of refraction" (optimiz\$5 optimum optimal).ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:33
S57	0	(multilayer stack).ab. thickness "index of refraction" (optimiz\$5 or optimum or optimal).ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:34
S58	0	(multilayer reflectivity).ab. thickness "index of refraction" (optimiz\$5 or optimum or optimal).ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:34
S59	0	(multilayer reflectivity (optimiz\$6 or optimum or optimal)).ab. thickness "index of refraction"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:35
S60	21	(multilayer reflectivity (optimiz\$6 or optimum or optimal)).ab. thickness	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:35
S61	10	(multilayer stack reflectivity (optimiz\$6 or optimum or optimal)).ab. thickness	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:36

S62	2	(multilayer stack reflectivity sensitivity (optimiz\$6 or optimum or optimal).ab. thickness	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:37
S63	2	(multilayer stack (optimiz\$6 or optimum or optimal).ab. thickness (reflectivity with sensitivity)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:37
S64	2	(multilayer stack (optimiz\$6 or optimum or optimal).ab. (reflectivity with sensitivity)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:38
S65	13	(multilayer same stack same (optimiz\$6 or optimum or optimal) (reflectivity with sensitivity)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:39
S67	9	S65 (simulat\$5 or model\$5)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:44
S68	10	"optimal reflectivity value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:53
S69	0	"optimum reflectivity value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:53
S70	0	"optimiz\$5 reflectivity value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:47
S71	0	"optimiz\$5 adj3 reflectivity value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:54
S72	0	"optimiz\$5 with reflectivity with value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:53
S73	0	"optim5 with reflectivity with value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:47

S74	0	"optim\$5 with reflectivity with value"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:47
S75	2	"optimal reflectance value"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:53
S76	3	"optimum reflectance value"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:53
S77	0	"optimiz\$5 with reflectance with value"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:53
S78	0	"optimiz\$5 adj3 reflectance value"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 13:54
S79	2149	703/2.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 14:31
S80	2	S79 (reflectivity or reflectance) with sensitivity	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 14:44
S81	0	S79 multilayer stack sensitivity extrema optimize	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 14:44
S82	0	S79 multilayer stack sensitivity extrema optimiz \$5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/03/14 14:44
S83	2316	703/2.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:51
S84	19	"lithography optimization"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52

S85	3852	(Reflect\$8 optimiz\$8).ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S86	17	"optimal reflectivity value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S87	153	reflectivity optimization multilayer stack lithography	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S88	2	S87 parameter extrema variable	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S89	1	S87 "R+ S"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S90	2	extrema with cost with reflectiv\$6	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S91	2	(optimal refraction stack). ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S92	14	(optim\$8 refraction stack). ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S93	2	extrema with cost with sensitiv\$6	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S94	5145	"R+ S"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S95	17	S94 reflectivity sensitivity	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52

S96	9	S84 stack	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S97	2	S96 reflectivity	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S98	0	"Reflectivity plus Sensitivity"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S99	19	lithography adj optimiza\$8	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S100	0	"lithography optimiza\$8"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S101	104	lithography adj4 optimiza\$8	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S102	0	(reflectiv\$6 optimiz&7).ti.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S103	28	(reflectiv\$6 optimiz\$7).ti.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S104	337	lithography with optimiza\$8	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S105	0	S104 "Reflectivity plus Sensitivity"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S106	14091	Reflect\$8 with optimiz\$8	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52

S107	30	"Reflectivity" with "Sensitivity" with cost	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S108	1	S104 "R+ S"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S109	123	S85 lithography	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S110	39	S109 refraction	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S111	2	"Reflectivity" with "Sensitivity" with lithography	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S112	509	reflectivity optimization multilayer stack	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S113	7	"reflectivity optimization"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S114	2	"20050114094"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S115	22408	Lithography.ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S116	0	S115 (optimal refraction stack).ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S117	0	S115 (optimiz\$7 reflectiv&5).ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52

S118	14	S115 (optimiz\$7 reflectiv\$5). ab.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S119	2	extrema same reflectiv\$6 same multilayer same stack	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S120	54	sensitiv\$6 same reflectiv\$6 same multilayer same stack	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S121	188581	Photolithography or lithography	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S122	2	extrema with reflectiv\$6 with input	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S123	57	S94 lithography	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S124	2	"Reflectivity" with "Sensitivity" with cost with function	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S125	4	(lithography same optimization) (multilayer with stack)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S126	3	S125 reflectiv\$6	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S127	114	lithography adj5 optimiza\$8	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52

S128	41	("2197719" "3052552" "3664962" "3872021" "3912817" "4148872" "4150112" "4156715" "4156716" "4157385" "4159315" "4160054" "4160820" "4208431" "4217368" "4224345" "4271199" "4352825" "4585649" "4753790" "4828845" "4842762" "4952407" "5017385" "5073389" "5256402" "5380530" "5391315" "5629035" "5645821" "5698215" "5713738" "5736175" "5756074" "5824291" "5879728").PN. OR ("6471945").URPN.	US-PGPUB; USPAT; USOCR	AND	ON	2007/08/21 10:52
S129	2	"6471945".pn.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S130	0	(multilayer stack).ab. thickness "index of refraction" (optimiz\$5 optimum optimal).ab.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S131	0	(multilayer stack).ab. thickness "index of refraction" (optimiz\$5 or optimum or optimal).ab.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S132	0	(multilayer reflectivity).ab. thickness "index of refraction" (optimiz\$5 or optimum or optimal).ab.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S133	0	(multilayer reflectivity (optimiz\$6 or optimum or optimal)).ab. thickness "index of refraction"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S134	21	(multilayer reflectivity (optimiz\$6 or optimum or optimal)).ab. thickness	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S135	10	(multilayer stack reflectivity (optimiz\$6 or optimum or optimal)).ab. thickness	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S136	2	(multilayer stack reflectivity sensitivity (optimiz\$6 or optimum or optimal)).ab. thickness	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52

S137	2	(multilayer stack (optimiz\$6 or optimum or optimal).ab. thickness (reflectivity with sensitivity))	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S138	2	(multilayer stack (optimiz\$6 or optimum or optimal).ab. (reflectivity with sensitivity))	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S139	14	(multilayer same stack same (optimiz\$6 or optimum or optimal)) (reflectivity with sensitivity))	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S140	10	S139 (simulat\$5 or model \$5)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S141	17	"optimal reflectivity value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S142	0	"optimiz\$5 adj3 reflectance value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S143	2316	703/2.ccls.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S144	2	S83 (reflectivity or reflectance) with sensitivity	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S145	0	"optimum reflectivity value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S146	0	"optim5 with reflectivity with value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S147	0	"optim\$5 with reflectivity with value"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52

S148	2	"optimal reflectance value"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S149	3	"optimum reflectance value"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S150	0	"optimiz\$5 with reflectance with value"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S151	0	"optimiz\$5 reflectivity value"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S152	0	"optimiz\$5 adj3 reflectivity value"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S153	0	"optimiz\$5 with reflectivity with value"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S154	0	S83 multilayer stack sensitivity extrema optimize	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S155	0	S83 multilayer stack sensitivity extrema optimiz \$5	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2007/08/21 10:52
S156	0	"simulate multilayer stack"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/04/22 14:11
S157	0	"simulat\$4 multilayer stack"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/04/22 14:11
S158	1	simulat\$4 near2 multilayer near2 stack	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/04/22 14:12

S159	:5	model\$4 near2 multilayer near2 stack	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/04/22 14:13
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